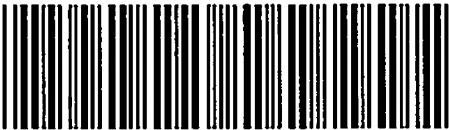


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/030,070	LETELLIER, PHILIPPE	
	Examiner	Art Unit	
	Annan Q. Shang	2617	

SEARCHED			
Class	Subclass	Date	Examiner
725	34-36,39-43,97,109,110-113	2/27/2006	A.S.
709	203-207	2/27/2006	A.S.
709	230-231	2/27/2006	A.S.

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR